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# Effect of Ni substitution on the microwave dielectric properties of cordierite

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## **Abstract**

Cordierite  $(Mg_2Al_4Si_5O_{18})$  is one of the silicates with low dielectric constant  $(\varepsilon_r)$ , which are expected for good candidate of millimeter wave dielectrics. Microwave dielectric properties of Ni substituted cordierite solid solutions;  $(Mg_{1-x}Ni_x)_2Al_4Si_5O_{18}$  have been investigated.  $(Mg_{1-x}Ni_x)_2Al_4Si_5O_{18}$  with no secondary phase was obtained in the compositions x range from 0 to 0.1. It was found that a very small amount of Ni substitution was effectively increased of the quality factor (Qf) value and the highest Qf value of 99,110 GHz was obtained in the composition x = 0.1. No remarkable composition dependence of the temperature coefficient of resonance frequency  $(\tau_f)$  was observed in the range from x = 0.05 to 0.2, On the other hand,  $\tau_f$  abruptly shifted toward negative value with increasing x from 0.3 to 0.5. The correlation between the crystal structure of cordierite and the microwave dielectric properties, particularly Qf is discussed. © 2006 Elsevier Ltd. All rights reserved.

Keywords: Microwave dielectric properties; Silicate; Cordierite

## 1. Introduction

The recent advances in wireless communication technology has considerably increased the demand for microwave dielectric materials. The important characteristics required for a dielectric material are suitable dielectric constant ( $\varepsilon_r$ ), high quality factor (Qf) and a nearly zero temperature coefficient of resonance frequency ( $\tau_f$ ). With the utilizable region of communication frequency expands to millimeter wave, a low  $\varepsilon_r$  is necessary to decrease the time for electronic signal transition. For this reason, microwave dielectric properties of silicates were investigated for millimeter wave applications. Silicates are composed of silicate tetrahedron with approximately 55% of covalent bonding. Consequently, silicates reveal a low  $\varepsilon_r$ , which are expected for good candidate of millimeter wave dielectrics.

Among the systems of MgO–Al<sub>2</sub>O<sub>3</sub>–SiO<sub>2</sub>, cordierite (Mg<sub>2</sub>Al<sub>4</sub>Si<sub>5</sub>O<sub>18</sub>) is characterized by a lower  $\varepsilon_r^{-1}$  and low coefficient of thermal expansion. The  $\varepsilon_r$  of cordierite ceramics prepared by standard solid state reaction method showed 6.19 and its  $\tau_f$  exhibited –24 ppm/°C, which was more close to zero

compared to other isotropic silicates. The crystal structure of cordierite consists of hexagonal rings formed by corner sharing (Si,Al)O<sub>4</sub> tetrahedron in the a-b plane. Because of the structural anisotropy, the cordierite reveals large anisotropy in coefficients of thermal expansion, characterizing by negative value for c-axis and positive value for a- or b-axis.

This study investigated the effects of Ni substitution on the microwave dielectric properties of cordierite ceramics. In addition, we discussed the relationship between crystal structure and microwave dielectric properties, particularly *Qf* from the viewpoint of crystal structure refined by Rietveld analysis.

# 2. Experimental

Ni substituted cordierite solid solutions were synthesized by conventional solid-state reaction method. General formula  $(Mg_{1-x}Ni_x)_2Al_4Si_5O_{18}$   $(0 \le x \le 0.5)$  was synthesized using a mixed oxide route with raw materials of  $Mg(OH)_2$  (purity of 99.98%), NiO (purity of 99.9%),  $Al_2O_3$  (purity of 99.99%) and  $SiO_2$  (purity of 99.9%). These powders were weighed in their appropriate ratios. Then they were mixed for 24 h in ethanol using  $ZrO_2$  ball. The slurry was then dried calcined at  $1300-1355\,^{\circ}C$  for 3 h in air. The calcined powders were re-

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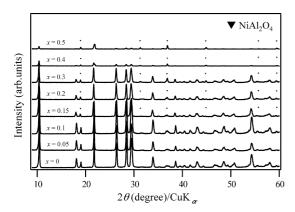


Fig. 1. XRD patterns of  $(Mg_{1-x}Ni_x)_2Al_4Si_5O_{18}$  solid solutions.

milled for 24 h in ethanol. After drying and granulation, the powders were uniaxially pressed at 20 MPa into pellets. The pellets were cold isostatically pressed under pressure of 200 MPa and sintered at 1390-1440 °C for 2h. Densities of the samples were measured by the Archimedes' method. Crystalline phases were identified by X-ray powder diffraction method (XRD; X'pert MPD, Philips) using Cu Kα radiation. Lattice constants were refined by the whole-powder-pattern decomposition (WPPF<sup>3</sup>) program. Crystal structure of the selected samples;  $(Mg_{1-x}Ni_x)_2Al_4Si_5O_{18}$   $(0 \le x \le 0.5)$  with x of 0, 0.1 were refined by using the Rietveld analysis (RIETAN-2000 program<sup>4</sup>). Rietveld analysis was performed using approximately 29,800 intensity data collected in the  $2\theta$  range from  $3^{\circ}$  to  $152^{\circ}$  in the composition x = 0 and approximately 25,200 intensity data collected in the  $2\theta$  range from  $4^{\circ}$  to  $130^{\circ}$  in the composition x = 0.1. Temperature factor of each ion determined by Gibbs<sup>5</sup> was used for this analysis. Lattice constants and the Rietveld refinement was carried out using a synchrotron radiation powder diffraction data obtained by a multiple  $2\theta$  detector system (MDS) at BL-4B2 in photon factory of the high energy accelerator research organization (PF-KEK), Tsukuba, Japan. Microwave dielectric properties were measured by Hakki and Coleman's method<sup>6</sup> in the  $TE_{01\delta}$  mode using a network analyzer (HP-8757, Hewlett Packard). The  $\tau_f$  was measured in the temperature range between 20 and 80 °C.

# 3. Results

XRD patterns of  $(Mg_{1-x}Ni_x)_2Al_4Si_5O_{18}$   $(0 \le x \le 0.5)$  solid solutions are shown in Fig. 1. It can be seen that cordierite with no secondary phase was obtained in the compositions x range from 0 to 0.1, whereas the cordierite solid solutions at a higher

Table 1  $(Mg_{1-x}Ni_x)_2Al_4Si_5O_{18}$  (x=0), S.G. Cccm No.66 orthorhombic, a=17.063(2) Å, b=9.745(1) Å, c=9.337(1) Å, V=1552(1) Å<sup>3</sup>

Atom	x	У	z	B (Å)	
Mg	0.3358(2)	0	1/4	0.23	
Al (1)	1/4	1/4	0.2505(5)	0.22	
A1 (2)	0.0531(2)	0.3060(3)	0	0.25	
Si (1)	0	1/2	1/4	0.2	
Si (2)	0.1933(2)	0.0830(3)	0	0.26	
Si (3)	0.1347(2)	0.7654(3)	0	0.23	
O(1)	0.2394(2)	0.9024(4)	0.3766(4)	0.27	
O(2)	0.0648(2)	0.5830(4)	0.3349(4)	0.24	
O(3)	0.8223(2)	0.6922(4)	0.3602(5)	0.31	
O (4)	0.0465(3)	0.7556(6)	0	0.25	
O(5)	0.1304(4)	0.1760(6)	0	0.65	
O(6)	0.1651(3)	-0.0723(6)	0	0.54	

 $R_{\rm wp} = 29.63\%$ ,  $R_{\rm I} = 13.03\%$ ,  $R_{\rm F} = 3.56\%$ , S = 1.4753%.

compositions higher than x=0.15 contained NiAl<sub>2</sub>O<sub>4</sub> phases. This secondary phase remarkably increased with increasing x from 0.3. The lattice parameters of  $(Mg_{1-x}Ni_x)_2Al_4Si_5O_{18}$   $(0 \le x \le 0.1)$  solid solutions were determined by the WPPF (Fig. 2). Slight composition dependence of lattice constants was observed. The lattice constants were decreased with increasing the composition x, because the ionic radii of Ni<sup>2+</sup> is smaller than that of  $Mg^{2+7}$ . Structure parameters of  $(Mg_{1-x}Ni_x)_2Al_4Si_5O_{18}$  (x=0, 0.1) were refined by the Rietveld method as listed in Table 1.

Densities  $(\rho)$  and microwave dielectric properties of  $(Mg_{1-x}Ni_x)_2Al_4Si_5O_{18}$  solid solutions as a function of composition x are shown in Fig. 3. Both  $\varepsilon_r$  and  $\rho$  monotonously increased with increasing composition x from 0 to 0.5. Qf was improved in the range of  $0 < x \le 0.1$ . The highest value of 99,110 GHz was obtained at the composition x = 0.1. The value decreased with increasing x from 0.15. No remarkable composition dependence of  $\tau_f$  was observed in the ranges x = 0.05-0.2, On the other hand,  $\tau_f$  abruptly shifted toward negative value in the compositions x higher than 0.3.

## 4. Discussion

The behavior of  $\varepsilon_r$  as a function of the composition was similar to that of  $\rho$ .  $\varepsilon_r$  depended on the sintering temperature, meaning that dense ceramics reveals the high  $\varepsilon_r^8$ . Therefore,  $\varepsilon_r$  of the cordierite solid solutions are mainly affected by the bulk density. In order to investigate the origin of improved Qf value of Ni substituted cordierite, the crystal structure of  $(Mg_{1-x}Ni_x)_2Al_4Si_5O_{18}$  (x=0.1) was compared to

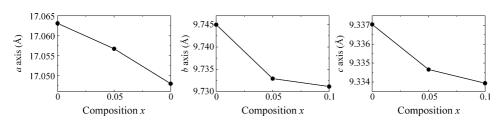


Fig. 2. Lattice constants of  $(Mg_{1-x}Ni_x)_2Al_4Si_5O_{18}$  solid solutions as a function of composition x.

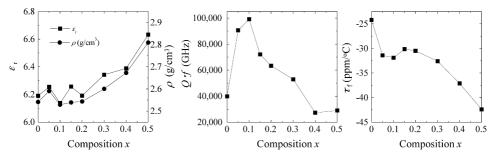


Fig. 3. Densities and microwave dielectric properties of  $(Mg_{1-x}Ni_x)_2Al_4Si_5O_{18}$  solid solutions as a function of composition x.

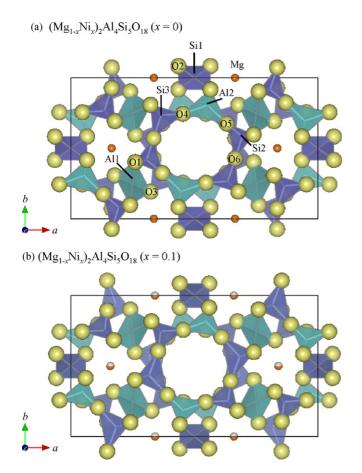


Fig. 4. Crystal Structures of (a)  $(Mg_{1-x}Ni_x)_2Al_4Si_5O_{18}$  (x=0) and (b)  $(Mg_{1-x}Ni_x)_2Al_4Si_5O_{18}$  (x=0.1).

that of the composition x=0. Fig. 4 illustrates the crystal structures obtained by using the crystal parameters listed on Tables 1 and 2. In this crystal structure, we focus on the symmetry of hexagonal rings composed of corner sharing (Si,Al)O<sub>4</sub> tetrahedron in the a-b plane. Fig. 4 shows that the rings of  $(Mg_{1-x}Ni_x)_2Al_4Si_5O_{18}$  at the composition x=0.1 was close to equilateral hexagonal rings. In other word, the hexagonal rings of  $(Mg_{1-x}Ni_x)_2Al_4Si_5O_{18}$  with x=0.1 are more isotropic than that of  $(Mg_{1-x}Ni_x)_2Al_4Si_5O_{18}$  with x=0. We suggest that the slight change of the hexagonal ring cause improvement of Qf. It was considered that  $\tau_f$  was influenced by slight variations of crystal structure in the range x of 0–0.1, since no secondary phase was observed. On the other hand,  $\tau_f$  might be sensitive to the

Table 2  $(Mg_{1-x}Ni_x)_2Al_4Si_5O_{18}$  (x=0.1), S.G. Cccm No.66 orthorhombic, a=17.047(2) Å, b=9.731(1) Å, c=9.333(2) Å, V=1548(1) Å<sup>3</sup>

Atom	g	x	у	z	B (Å)
Mg	0.895(4)	0.3403(2)	0	1/4	0.23
Ni	0.104(4)	0.3403(2)	0	1/4	0.23
Al (1)	1	1/4	1/4	0.2473(5)	0.22
A1 (2)	1	0.0462(2)	0.3152(4)	0	0.25
Si (1)	1	0	1/2	1/4	0.2
Si (2)	1	0.1837(2)	0.0654(4)	0	0.26
Si (3)	1	0.1365(2)	0.7531(4)	0	0.23
O(1)	1	0.2405(3)	0.9008(4)	0.3759(5)	0.27
O(2)	1	0.0593(3)	0.5850(5)	0.3522(5)	0.24
O(3)	1	0.8262(2)	0.6830(5)	0.3424(5)	0.31
O(4)	1	0.0454(4)	0.7438(7)	0	0.25
O(5)	1	0.1096(4)	0.2055(7)	0	0.65
O (6)	1	0.1468(4)	-0.1061(6)	0	0.54

 $R_{\text{WD}} = 26.54\%$ ,  $R_{\text{I}} = 9.33\%$ ,  $R_{\text{F}} = 2.88\%$ , S = 1.3802%.

secondary phase of NiAl<sub>2</sub>O<sub>4</sub>, in the range over x = 0.3. According to other researchers, it has been reported that  $\tau_f$  of MgAl<sub>2</sub>O<sub>4</sub> and ZnAl<sub>2</sub>O<sub>4</sub> show -75 and -79 ppm/°C, respectively<sup>9,10</sup>. We consider that  $\tau_f$  of NiAl<sub>2</sub>O<sub>4</sub> owing to same crystal structure, which results in the remarkable composition dependence.

## 5. Conclusion

Microwave dielectric properties of Ni substituted cordierite solid solutions;  $(Mg_{1-x}Ni_x)_2Al_4Si_5O_{18}$  have been investigated. Single phase cordierites were obtained in the compositions x range from 0 to 0.1. Secondary phase was observed at the compositions of larger than x=0.3.  $\varepsilon_r$  of  $(Mg_{1-x}Ni_x)_2Al_4Si_5O_{18}$  solid solution slightly increased with increasing x. The highest Qf value of 99,110 GHz was obtained at the composition x=0.1.  $\tau_f$  varied from -24 ppm/°C to approximately -30 ppm/°C in the ranges x=0.05-0.2 without the influence of secondary phase. From Rietveld analysis's result, hexagonal rings composed of corner sharing  $(Si,Al)O_4$  tetrahedron in the a-b plane in the composition x=0.1 were more isotropic than that of x=0, suggesting that the Qf value was improved with the slight change of symmetry.

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